EB13C3C1H-42.800M



Series -RoHS Compliant (Pb-free) Low Current 3.3V 4 Pad 5mm x 7mm Ceramic SMD LVCMOS Oscillator

Frequency Tolerance/Stability ±100ppm over 0°C to +70°C

Duty Cycle -50 ±10(%)

l	- Logic Control / Additional Output
	Tri-State (High Impedance)

L Nominal Frequency

42.800MHz

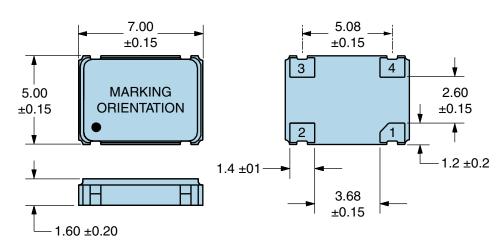
ELECTRICAL SPECIFICATIONS				
Nominal Frequency	42.800MHz			
Frequency Tolerance/Stability	±100ppm over 0°C to +70°C (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Ouput Load Change, First Year Aging at 25°C, Shock, and Vibration)			
Supply Voltage	3.3Vdc ±10%			
Input Current	12mA Maximum			
Output Voltage Logic High (Voh)	90% of Vdd Minimum			
Input Current Logic High (Ioh)	-8mA			
Output Voltage Logic Low (Vol)	10% of Vdd Maximum			
Input Current Logic Low (IoI)	+8mA			
Rise/Fall Time	4nSec Maximum (Measured at 20% to 80% of waveform)			
Duty Cycle	50 ±10(%) (Measured at 50% of waveform)			
Load Drive Capability	15pF Maximum			
Output Logic Type	CMOS			
Logic Control / Additional Output	Tri-State (High Impedance)			
Tri-State Input Voltage (Vih and Vil)	90% of Vdd Minimum or No Connect to Enable Output, 10% of Vdd Maximum to Disable Output (High Impedance)			
Standby Current	10µA Maximum (Disabled Output: High Impedance)			
One Sigma Clock Period Jitter	25pSec Maximum			
Start Up Time	10mSec Maximum			
Storage Temperature Range	-55°C to +125°C			

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ENVIRONMENTAL & MECHANICAL SPECIFICATIONS				
Fine Leak Test	MIL-STD-883, Method 1014, Condition A			
Gross Leak Test	MIL-STD-883, Method 1014, Condition C			
Mechanical Shock	MIL-STD-202, Method 213, Condition C			
Resistance to Soldering Heat	MIL-STD-202, Method 210			
Resistance to Solvents	MIL-STD-202, Method 215			
Solderability	MIL-STD-883, Method 2003			
Temperature Cycling	MIL-STD-883, Method 1010			
Vibration	MIL-STD-883, Method 2007, Condition A			

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MECHANICAL DIMENSIONS (all dimensions in millimeters)



PIN	CONNECTION
1	Tri-State
2 3	Ground
3	Output
4	Supply Voltage
LINE	MARKING
LINE 1	MARKING ECLIPTEK

Suggested Solder Pad Layout

All Dimensions in Millimeters



All Tolerances are ±0.1



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OUTPUT WAVEFORM & TIMING DIAGRAM



Test Circuit for CMOS Output



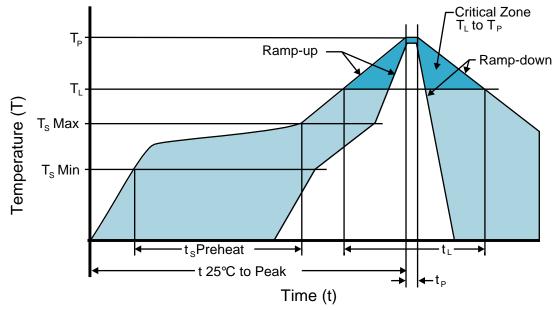
Note 1: An external 0.1μ F low frequency tantalum bypass capacitor in parallel with a 0.01μ F high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value \dot{C}_L includes sum of all probe and fixture capacitance.



Recommended Solder Reflow Methods



High Temperature Infrared/Convection

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T_s MAX to T_L (Ramp-up Rate)	3°C/second Maximum
Preheat	
- Temperature Minimum (T _s MIN)	150°C
 Temperature Typical (T_s TYP) 	175°C
 Temperature Maximum (T_s MAX) 	200°C
- Time (t _s MIN)	60 - 180 Seconds
Ramp-up Rate (T _L to T _P)	3°C/second Maximum
Time Maintained Above:	
- Temperature (T∟)	217°C
- Time (t∟)	60 - 150 Seconds
Peak Temperature (T _P)	260°C Maximum for 10 Seconds Maximum
Target Peak Temperature (T _P Target)	250°C +0/-5°C
Time within 5°C of actual peak (t _p)	20 - 40 seconds
Ramp-down Rate	6°C/second Maximum
Time 25°C to Peak Temperature (t)	8 minutes Maximum
Moisture Sensitivity Level	Level 1
Additional Notes	Temperatures shown are applied to body of device.



Recommended Solder Reflow Methods

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Low Temperature Infrared/Convection 240°C

T _s MAX to T _L (Ramp-up Rate)	5°C/second Maximum
Preheat	
- Temperature Minimum (T _s MIN)	N/A
- Temperature Typical (T _s TYP)	150°C
- Temperature Maximum (T _s MAX)	N/A
- Time (t _s MIN)	60 - 120 Seconds
Ramp-up Rate (T⊾ to T _P)	5°C/second Maximum
Time Maintained Above:	
- Temperature (T∟)	150°C
- Time (t∟)	200 Seconds Maximum
Peak Temperature (T _P)	240°C Maximum
Target Peak Temperature (T _P Target)	240°C Maximum 1 Time / 230°C Maximum 2 Times
Time within 5°C of actual peak (t_p)	10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time
Ramp-down Rate	5°C/second Maximum
Time 25°C to Peak Temperature (t)	N/A
Moisture Sensitivity Level	Level 1
Additional Notes	Temperatures shown are applied to body of device.

Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)

High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)